

Notice of References Cited	Application/Control No. 10/588,283	Applicant(s)/Patent Under Reexamination KAWASAKI ET AL.	
	Examiner JONATHAN C. LANGMAN	Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Look et al., "Characterization of homoepitaxial p-type ZnO grown by MBE", Applied Physics Letters, Volume 81, Number 10, September 2002, 1830-1832.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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